


<b>Search Notes</b>  	<b>Application/Control No.</b>  10629640	<b>Applicant(s)/Patent Under Reexamination</b>  AMER, MAHER
	<b>Examiner</b>  La Forgia, Christian	<b>Art Unit</b>  2131

SEARCHED			
Class	Subclass	Date	Examiner
380	28 AND parallel with scrambl\$3	11/30/06	clf
380	210 AND parallel with scrambl\$3	11/30/06	clf
380	268 AND parallel with scrambl\$3	11/30/06	clf
380	(28 or 210 or 268) and parallel near scrambl\$3	1/16/08	clf

SEARCH NOTES		
Search Notes	Date	Examiner
East Search - seen enclosed printout	11/28/06	clf
IEEE Search	11/28/06	clf
ACM Search	11/28/06	clf
Google Search	11/28/06	clf
Inventor Search	11/28/06	clf
Assignee Search	11/28/06	clf
Cases Reviewed for Double Patenting: 10/629,644	11/28/06	clf
EIC - for DW Choi document	11/28/06	clf
East search - see enclosed printout	4/16/07	clf
IEEE search	4/16/07	clf
ACM search	4/16/07	clf
Google Search	4/16/07	clf
East search - see enclosed printout	8/11/07	clf
IEEE search	8/11/07	clf
ACM search	8/11/07	clf
Google search	8/11/07	clf
updated EAST search - see enclosed prinout	1/16/08	clf

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	(serial near sequence).clm. same (bitwise near parallel).clm.	1/16/08	clf
	(serial near sequence).clm. and (bitwise near parallel).clm.	1/16/08	clf